

74AUP1T98-Q100

Low-power configurable gate with voltage-level translator

Rev. 1 — 19 May 2014

Product data sheet

1. General description

The 74AUP1T98-Q100 provides low-power, low-voltage configurable logic gate functions. Eight patterns of 3-bit input determine the output state. The user can choose the logic functions MUX, AND, OR, NAND, NOR, inverter and buffer. All inputs can be connected to V_{CC} or GND.

This device ensures a very low static and dynamic power consumption across the entire V_{CC} range from 2.3 V to 3.6 V.

The 74AUP1T98-Q100 is designed for logic-level translation applications. The input switching levels accept 1.8 V low-voltage CMOS signals, while operating from either a single 2.5 V or 3.3 V supply voltage.

The wide supply voltage range ensures normal operation as battery voltage drops from 3.6 V to 2.3 V.

This device is fully specified for partial power-down applications using I_{OFF} . The I_{OFF} circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

Schmitt trigger inputs make the circuit tolerant to slower input rise and fall times across the entire V_{CC} range.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - ◆ Specified from $-40\text{ }^{\circ}\text{C}$ to $+85\text{ }^{\circ}\text{C}$ and from $-40\text{ }^{\circ}\text{C}$ to $+125\text{ }^{\circ}\text{C}$
- Wide supply voltage range from 2.3 V to 3.6 V
- High noise immunity
- ESD protection:
 - ◆ MIL-STD-883, method 3015 Class 3A. Exceeds 5000 V
 - ◆ HBM JESD22-A114F Class 3A. Exceeds 5000 V
 - ◆ MM JESD22-A115-A exceeds 200 V ($C = 200\text{ pF}$, $R = 0\text{ }\Omega$)
- Low static power consumption; $I_{CC} = 1.5\text{ }\mu\text{A}$ (maximum)
- Latch-up performance exceeds 100 mA per JESD 78 Class II
- Inputs accept voltages up to 3.6 V
- Low noise overshoot and undershoot $< 10\%$ of V_{CC}
- I_{OFF} circuitry provides partial power-down mode operation



3. Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
74AUP1T98GW-Q100	-40 °C to +125 °C	SC-88	plastic surface-mounted package; 6 leads	SOT363

4. Marking

Table 2. Marking

Type number	Marking code
74AUP1T98GW-Q100	aR

5. Functional diagram

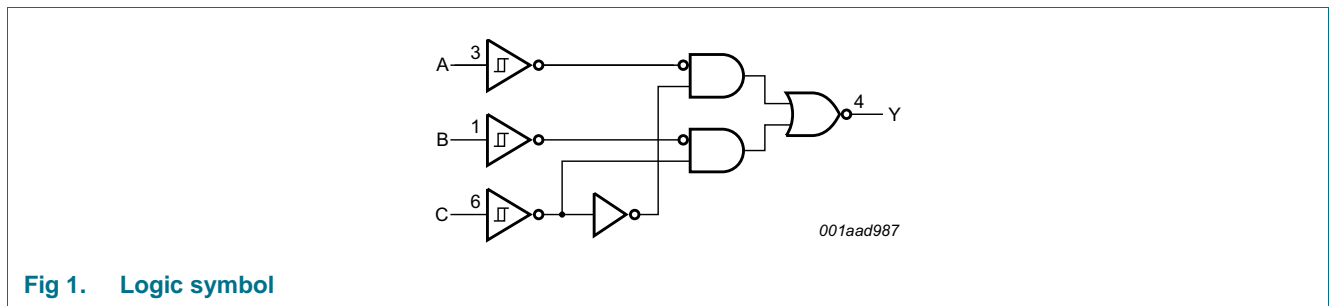


Fig 1. Logic symbol

6. Pinning information

6.1 Pinning

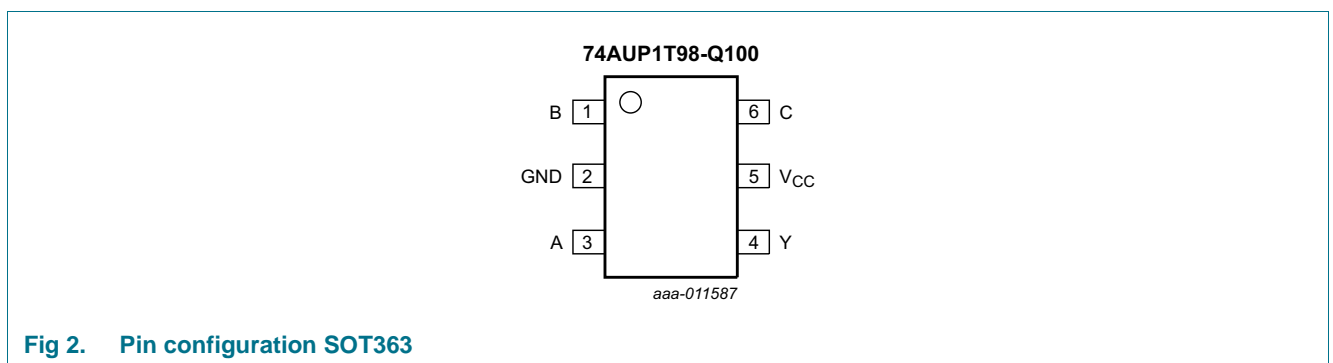


Fig 2. Pin configuration SOT363

6.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
B	1	data input
GND	2	ground (0 V)
A	3	data input
Y	4	data output
V _{CC}	5	supply voltage
C	6	data input

7. Functional description

Table 4. Function table^[1]

Input			Output
C	B	A	Y
L	L	L	H
L	L	H	H
L	H	L	L
L	H	H	L
H	L	L	H
H	L	H	L
H	H	L	H
H	H	H	L

[1] H = HIGH voltage level; L = LOW voltage level.

7.1 Logic configurations

Table 5. Function selection table

Logic function	Figure
2-input MUX (inverting)	see Figure 3
2-input NAND	see Figure 4
2-input NOR with one input inverted	see Figure 5
2-input AND with one input inverted	see Figure 5
2-input NAND with one input inverted	see Figure 6
2-input OR with one input inverted	see Figure 6
2-input NOR	see Figure 7
Buffer	see Figure 8
Inverter	see Figure 9

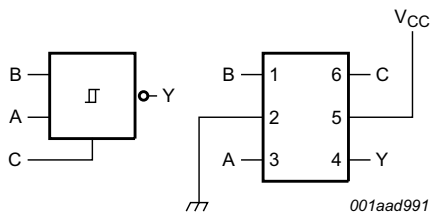


Fig 3. 2-input MUX (inverting)

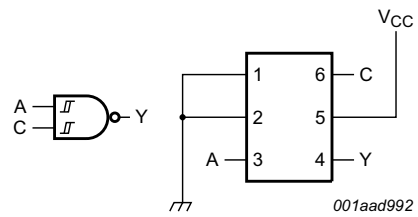


Fig 4. 2-input NAND gate

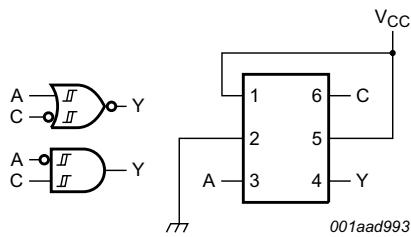


Fig 5. 2-input AND gate with input A inverted or 2-input NOR gate with input C inverted

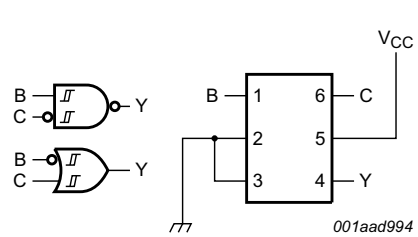


Fig 6. 2-input OR gate with input B inverted or 2-input NAND gate with input C inverted

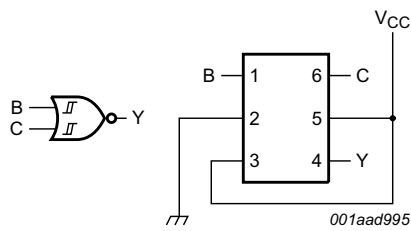


Fig 7. 2-input NOR gate

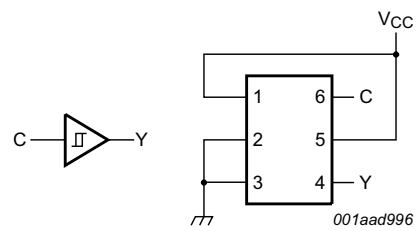


Fig 8. Buffer

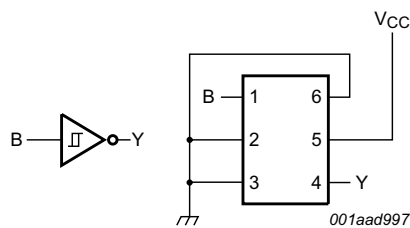


Fig 9. Inverter

8. Limiting values

Table 6. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+4.6	V
I_{IK}	input clamping current	$V_I < 0$ V	-50	-	mA
V_I	input voltage		[1] -0.5	+4.6	V
I_{OK}	output clamping current	$V_O < 0$ V	-50	-	mA
V_O	output voltage	Active mode and Power-down mode	[1] -0.5	+4.6	V
I_O	output current	$V_O = 0$ V to V_{CC}	-	± 20	mA
I_{CC}	supply current		-	+50	mA
I_{GND}	ground current		-50	-	mA
T_{stg}	storage temperature		-65	+150	°C
P_{tot}	total power dissipation	$T_{amb} = -40$ °C to +125 °C	[2] -	250	mW

[1] The minimum input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] For SC-88 package: above 87.5 °C the value of P_{tot} derates linearly with 4.0 mW/K.

9. Recommended operating conditions

Table 7. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		2.3	3.6	V
V_I	input voltage		0	3.6	V
V_O	output voltage	Active mode	0	V_{CC}	V
		Power-down mode; $V_{CC} = 0$ V	0	3.6	V
T_{amb}	ambient temperature		-40	+125	°C

10. Static characteristics

Table 8. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
T_{amb} = 25 °C						
V _{T+}	positive-going threshold voltage	V _{CC} = 2.3 V to 2.7 V	0.60	-	1.10	V
		V _{CC} = 3.0 V to 3.6 V	0.75	-	1.16	V
V _{T-}	negative-going threshold voltage	V _{CC} = 2.3 V to 2.7 V	0.35	-	0.60	V
		V _{CC} = 3.0 V to 3.6 V	0.50	-	0.85	V
V _H	hysteresis voltage	(V _H = V _{T+} - V _{T-})				
		V _{CC} = 2.3 V to 2.7 V	0.23	-	0.60	V
		V _{CC} = 3.0 V to 3.6 V	0.25	-	0.56	V
V _{OH}	HIGH-level output voltage	V _I = V _{T+} or V _{T-}				
		I _O = -20 μA; V _{CC} = 2.3 V to 3.6 V	V _{CC} - 0.1	-	-	V
		I _O = -2.3 mA; V _{CC} = 2.3 V	2.05	-	-	V
		I _O = -3.1 mA; V _{CC} = 2.3 V	1.9	-	-	V
		I _O = -2.7 mA; V _{CC} = 3.0 V	2.72	-	-	V
		I _O = -4.0 mA; V _{CC} = 3.0 V	2.6	-	-	V
V _{OL}	LOW-level output voltage	V _I = V _{T+} or V _{T-}				
		I _O = 20 μA; V _{CC} = 2.3 V to 3.6 V	-	-	0.10	V
		I _O = 2.3 mA; V _{CC} = 2.3 V	-	-	0.31	V
		I _O = 3.1 mA; V _{CC} = 2.3 V	-	-	0.44	V
		I _O = 2.7 mA; V _{CC} = 3.0 V	-	-	0.31	V
		I _O = 4.0 mA; V _{CC} = 3.0 V	-	-	0.44	V
I _I	input leakage current	V _I = GND to 3.6 V; V _{CC} = 0 V to 3.6 V	-	-	±0.1	μA
I _{OFF}	power-off leakage current	V _I or V _O = 0 V to 3.6 V; V _{CC} = 0 V	-	-	±0.1	μA
ΔI _{OFF}	additional power-off leakage current	V _I or V _O = 0 V to 3.6 V; V _{CC} = 0 V to 0.2 V	-	-	±0.2	μA
I _{CC}	supply current	V _I = GND or V _{CC} ; I _O = 0 A; V _{CC} = 2.3 V to 3.6 V	-	-	1.2	μA
C _I	input capacitance	V _{CC} = 0 V to 3.6 V; V _I = GND or V _{CC}	-	0.8	-	pF
C _O	output capacitance	V _O = GND; V _{CC} = 0 V	-	1.7	-	pF
T_{amb} = -40 °C to +85 °C						
V _{T+}	positive-going threshold voltage	V _{CC} = 2.3 V to 2.7 V	0.60	-	1.10	V
		V _{CC} = 3.0 V to 3.6 V	0.75	-	1.19	V
V _{T-}	negative-going threshold voltage	V _{CC} = 2.3 V to 2.7 V	0.35	-	0.60	V
		V _{CC} = 3.0 V to 3.6 V	0.50	-	0.85	V
V _H	hysteresis voltage	(V _H = V _{T+} - V _{T-})				
		V _{CC} = 2.3 V to 2.7 V	0.10	-	0.60	V
		V _{CC} = 3.0 V to 3.6 V	0.15	-	0.56	V

Table 8. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{OH}	HIGH-level output voltage	V _I = V _{T+} or V _{T-}				
		I _O = -20 μA; V _{CC} = 2.3 V to 3.6 V	V _{CC} - 0.1	-	-	V
		I _O = -2.3 mA; V _{CC} = 2.3 V	1.97	-	-	V
		I _O = -3.1 mA; V _{CC} = 2.3 V	1.85	-	-	V
		I _O = -2.7 mA; V _{CC} = 3.0 V	2.67	-	-	V
		I _O = -4.0 mA; V _{CC} = 3.0 V	2.55	-	-	V
V _{OL}	LOW-level output voltage	V _I = V _{T+} or V _{T-}				
		I _O = 20 μA; V _{CC} = 2.3 V to 3.6 V	-	-	0.1	V
		I _O = 2.3 mA; V _{CC} = 2.3 V	-	-	0.33	V
		I _O = 3.1 mA; V _{CC} = 2.3 V	-	-	0.45	V
		I _O = 2.7 mA; V _{CC} = 3.0 V	-	-	0.33	V
		I _O = 4.0 mA; V _{CC} = 3.0 V	-	-	0.45	V
I _I	input leakage current	V _I = GND to 3.6 V; V _{CC} = 0 V to 3.6 V	-	-	±0.5	μA
I _{OFF}	power-off leakage current	V _I or V _O = 0 V to 3.6 V; V _{CC} = 0 V	-	-	±0.5	μA
ΔI _{OFF}	additional power-off leakage current	V _I or V _O = 0 V to 3.6 V; V _{CC} = 0 V to 0.2 V	-	-	±0.5	μA
I _{CC}	supply current	V _I = GND or V _{CC} ; I _O = 0 A; V _{CC} = 2.3 V to 3.6 V	-	-	1.5	μA
ΔI _{CC}	additional supply current	V _{CC} = 2.3 V to 2.7 V; I _O = 0 A	[1]	-	4	μA
		V _{CC} = 3.0 V to 3.6 V; I _O = 0 A	[2]	-	12	μA
T_{amb} = -40 °C to +125 °C						
V _{T+}	positive-going threshold voltage	V _{CC} = 2.3 V to 2.7 V	0.60	-	1.10	V
		V _{CC} = 3.0 V to 3.6 V	0.75	-	1.19	V
V _{T-}	negative-going threshold voltage	V _{CC} = 2.3 V to 2.7 V	0.33	-	0.64	V
		V _{CC} = 3.0 V to 3.6 V	0.46	-	0.85	V
V _H	hysteresis voltage	(V _H = V _{T+} - V _{T-})				
		V _{CC} = 2.3 V to 2.7 V	0.10	-	0.60	V
		V _{CC} = 3.0 V to 3.6 V	0.15	-	0.56	V
V _{OH}	HIGH-level output voltage	V _I = V _{T+} or V _{T-}				
		I _O = -20 μA; V _{CC} = 2.3 V to 3.6 V	V _{CC} - 0.11	-	-	V
		I _O = -2.3 mA; V _{CC} = 2.3 V	1.77	-	-	V
		I _O = -3.1 mA; V _{CC} = 2.3 V	1.67	-	-	V
		I _O = -2.7 mA; V _{CC} = 3.0 V	2.40	-	-	V
		I _O = -4.0 mA; V _{CC} = 3.0 V	2.30	-	-	V
V _{OL}	LOW-level output voltage	V _I = V _{T+} or V _{T-}				
		I _O = 20 μA; V _{CC} = 2.3 V to 3.6 V	-	-	0.11	V
		I _O = 2.3 mA; V _{CC} = 2.3 V	-	-	0.36	V
		I _O = 3.1 mA; V _{CC} = 2.3 V	-	-	0.50	V
		I _O = 2.7 mA; V _{CC} = 3.0 V	-	-	0.36	V
		I _O = 4.0 mA; V _{CC} = 3.0 V	-	-	0.50	V
I _I	input leakage current	V _I = GND to 3.6 V; V _{CC} = 0 V to 3.6 V	-	-	±0.75	μA

Table 8. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{OFF}	power-off leakage current	V_I or $V_O = 0$ V to 3.6 V; $V_{CC} = 0$ V	-	-	± 0.75	μ A
ΔI_{OFF}	additional power-off leakage current	V_I or $V_O = 0$ V to 3.6 V; $V_{CC} = 0$ V to 0.2 V	-	-	± 0.75	μ A
I_{CC}	supply current	$V_I = GND$ or V_{CC} ; $I_O = 0$ A; $V_{CC} = 2.3$ V to 3.6 V	-	-	3.5	μ A
ΔI_{CC}	additional supply current	$V_{CC} = 2.3$ V to 2.7 V; $I_O = 0$ A	[1]	-	7	μ A
		$V_{CC} = 3.0$ V to 3.6 V; $I_O = 0$ A	[2]	-	22	μ A

[1] One input at 0.3 V or 1.1 V, other input at V_{CC} or GND.

[2] One input at 0.45 V or 1.2 V, other input at V_{CC} or GND.

11. Dynamic characteristics

Table 9. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 11](#).

Symbol	Parameter	Conditions	25 °C			-40 °C to +125 °C			Unit
			Min	Typ ^[1]	Max	Min	Max (85 °C)	Max (125 °C)	
$V_{CC} = 2.3$ V to 2.7 V; $V_I = 1.65$ V to 1.95 V									
t_{pd}	propagation delay	A, B, C to Y; see Figure 10 [2]							
		$C_L = 5$ pF	2.0	3.6	5.7	0.5	6.8	7.5	ns
		$C_L = 10$ pF	2.5	4.2	6.3	1.0	7.9	8.7	ns
		$C_L = 15$ pF	2.9	4.6	6.9	1.0	8.7	9.6	ns
		$C_L = 30$ pF	3.9	5.8	8.3	1.5	10.8	11.9	ns
$V_{CC} = 2.3$ V to 2.7 V; $V_I = 2.3$ V to 2.7 V									
t_{pd}	propagation delay	A, B, C to Y; see Figure 10 [2]							
		$C_L = 5$ pF	1.7	3.4	5.6	0.5	6.0	6.6	ns
		$C_L = 10$ pF	2.1	4.0	6.3	1.0	7.1	7.9	ns
		$C_L = 15$ pF	2.5	4.5	6.9	1.0	7.9	8.7	ns
		$C_L = 30$ pF	3.4	5.6	8.4	1.5	10.0	11.0	ns
$V_{CC} = 2.3$ V to 2.7 V; $V_I = 3.0$ V to 3.6 V									
t_{pd}	propagation delay	A, B, C to Y; see Figure 10 [2]							
		$C_L = 5$ pF	1.3	3.2	5.2	0.5	5.5	6.1	ns
		$C_L = 10$ pF	1.8	3.7	5.9	1.0	6.5	7.2	ns
		$C_L = 15$ pF	2.2	4.2	6.5	1.0	7.4	8.2	ns
		$C_L = 30$ pF	3.1	5.4	7.9	1.5	9.5	10.5	ns
$V_{CC} = 3.0$ V to 3.6 V; $V_I = 1.65$ V to 1.95 V									
t_{pd}	propagation delay	A, B, C to Y; see Figure 10 [2]							
		$C_L = 5$ pF	2.0	2.9	4.1	0.5	8.0	8.8	ns
		$C_L = 10$ pF	2.4	3.5	4.8	1.0	8.5	9.4	ns
		$C_L = 15$ pF	2.8	3.9	5.4	1.0	9.1	10.1	ns
		$C_L = 30$ pF	3.6	5.1	6.9	1.5	9.8	10.8	ns

Table 9. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V); for test circuit, see Figure 11.

Symbol	Parameter	Conditions	25 °C			–40 °C to +125 °C			Unit
			Min	Typ ^[1]	Max	Min	Max (85 °C)	Max (125 °C)	
V_{CC} = 3.0 V to 3.6 V; V_I = 2.3 V to 2.7 V									
t _{pd}	propagation delay	A, B, C to Y; see Figure 10 [2]							
		C _L = 5 pF	1.5	2.8	4.4	0.5	5.3	5.9	ns
		C _L = 10 pF	2.0	3.4	5.1	1.0	6.1	6.8	ns
		C _L = 15 pF	2.4	3.9	5.7	1.0	6.8	7.5	ns
		C _L = 30 pF	3.4	5.0	7.2	1.5	8.5	9.4	ns
V_{CC} = 3.0 V to 3.6 V; V_I = 3.0 V to 3.6 V									
t _{pd}	propagation delay	A, B, C to Y; see Figure 10 [2]							
		C _L = 5 pF	1.3	2.8	4.4	0.5	4.7	5.2	ns
		C _L = 10 pF	1.7	3.3	5.2	1.0	5.7	6.3	ns
		C _L = 15 pF	2.1	3.8	5.8	1.0	6.2	6.9	ns
		C _L = 30 pF	3.1	5.0	7.2	1.5	7.8	8.6	ns
T_{amb} = 25 °C									
C _{PD}	power dissipation capacitance	f _i = 1 MHz; V _I = GND to V _{CC} [3]							
		V _{CC} = 2.3 V to 2.7 V	-	3.6	-	-	-	-	pF
		V _{CC} = 3.0 V to 3.6 V	-	4.3	-	-	-	-	pF

- [1] All typical values are measured at nominal V_{CC}.
- [2] t_{pd} is the same as t_{PLH} and t_{PHL}
- [3] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).
 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:
 f_i = input frequency in MHz;
 f_o = output frequency in MHz;
 C_L = output load capacitance in pF;
 V_{CC} = supply voltage in V;
 N = number of inputs switching;
 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.

12. Waveforms

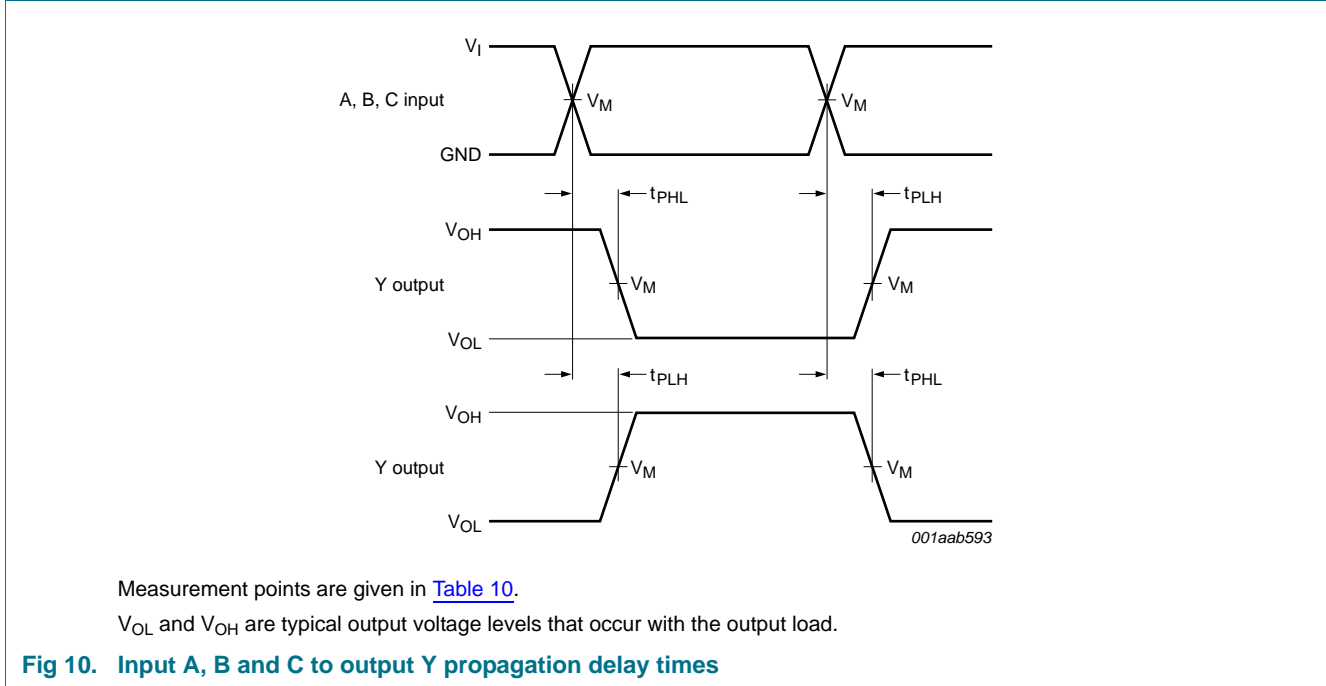
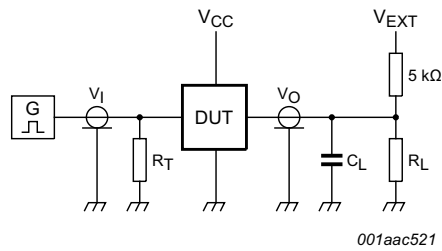


Table 10. Measurement points

Supply voltage	Output	Input		
V_{CC}	V_M	V_M	V_I	$t_r = t_f$
2.3 V to 3.6 V	$0.5 \times V_{CC}$	$0.5 \times V_I$	1.65 V to 3.6 V	≤ 3.0 ns



Test data is given in [Table 11](#).

Definitions for test circuit:

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

R_T = Termination resistance should be equal to the output impedance Z_o of the pulse generator.

V_{EXT} = External voltage for measuring switching times.

Fig 11. Test circuit for measuring switching times

Table 11. Test data

Supply voltage	Load		V_{EXT}		
V_{CC}	C_L	R_L [1]	t_{PLH} , t_{PHL}	t_{PZH} , t_{PHZ}	t_{PZL} , t_{PLZ}
2.3 V to 3.6 V	5 pF, 10 pF, 15 pF and 30 pF	5 kΩ or 1 MΩ	open	GND	$2 \times V_{CC}$

[1] For measuring enable and disable times, $R_L = 5 \text{ k}\Omega$. For measuring propagation delays, setup and hold times, and pulse width, $R_L = 1 \text{ M}\Omega$.

13. Package outline

Plastic surface-mounted package; 6 leads

SOT363

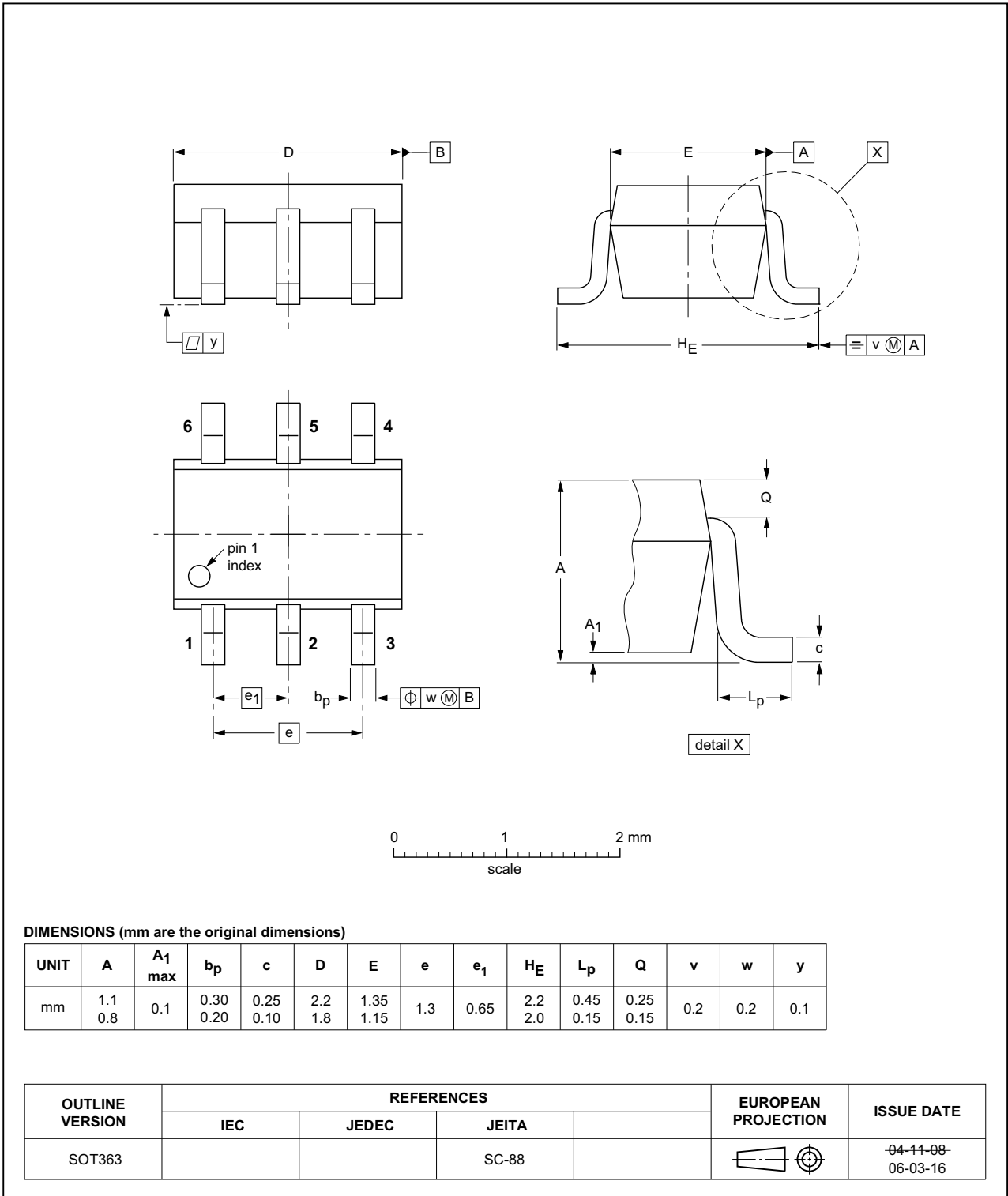


Fig 12. Package outline SOT363 (SC-88)

14. Abbreviations

Table 12. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal-Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MIL	Military
MM	Machine Model

15. Revision history

Table 13. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74AUP1T98_Q100 v.1	20140519	Product data sheet	-	-

16. Legal information

16.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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